

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/616,696	<b>Applicant(s)/Patent under Reexamination</b> SUGITA ET AL.
	<b>Examiner</b> Dah-Wei D. Yuan	<b>Art Unit</b> 1745

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner